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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	29
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x14b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb11f32es0-b-qfn32

Timers (Timer 0, Timer 1, Timer 2, Timer 3, Timer 4, and Timer 5)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2, Timer 3, Timer 4, and Timer 5 are 16-bit timers including the following features:

- Clock sources for all timers include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8
- LFOSC0 divided by 8 may be used to clock Timer 3 and Timer 4 in active or suspend/snooze power modes
- Timer 4 is a low-power wake source, and can be chained together with Timer 3
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture
- LFOSC0 capture
- Comparator 0 capture
- Configurable Logic output capture

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions.
- Baud rates up to $\text{SYSCLK}/2$ (transmit) or $\text{SYSCLK}/8$ (receive).
- 8- or 9-bit data.
- Automatic start and stop generation.
- Single-byte FIFO on transmit and receive.

I2C Slave (I2CSLAVE0)

The I2C Slave interface is a 2-wire, bidirectional serial bus that is compatible with the I2C Bus Specification 3.0. It is capable of transferring in high-speed mode (HS-mode) at speeds of up to 3.4 Mbps. Firmware can write to the I2C interface, and the I2C interface can autonomously control the serial transfer of data. The interface also supports clock stretching for cases where the core may be temporarily prohibited from transmitting a byte or processing a received byte during an I2C transaction. This module operates only as an I2C slave device.

The I2C module includes the following features:

- Standard (up to 100 kbps), Fast (400 kbps), Fast Plus (1 Mbps), and High-speed (3.4 Mbps) transfer speeds
- Support for slave mode only
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave address recognition
- Transmit and receive FIFOs (two byte) to help increase throughput in faster applications
- Hardware support for multiple slave addresses with the option to save the matching address in the receive FIFO

16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

Configurable Logic Units (CLU0, CLU1, CLU2, and CLU3)

The Configurable Logic block consists of multiple Configurable Logic Units (CLUs). CLUs are flexible logic functions which may be used for a variety of digital functions, such as replacing system glue logic, aiding in the generation of special waveforms, or synchronizing system event triggers.

- Four configurable logic units (CLUs), with direct-pin and internal logic connections
- Each unit supports 256 different combinatorial logic functions (AND, OR, XOR, muxing, etc.) and includes a clocked flip-flop for synchronous operations
- Units may be operated synchronously or asynchronously
- May be cascaded together to perform more complicated logic functions
- Can operate in conjunction with serial peripherals such as UART and SPI or timing peripherals such as timers and PCA channels
- Can be used to synchronize and trigger multiple on-chip resources (ADC, DAC, Timers, etc.)
- Asynchronous output may be used to wake from low-power states

Bootloader	Pins for Bootload Communication
Note: 1. The STK uses these pins for another purpose, so there is a special SMBus bootloader build for the STK only included in <i>AN945: EFM8 Factory Bootloader User Guide</i> that uses P1.2 (SDA) and P1.3 (SCL).	

Table 3.3. Summary of Pins for Bootload Mode Entry

Device Package	Pin for Bootload Mode Entry
QFN32	P3.7 / C2D
QFP32	P3.7 / C2D
QFN24	P3.0 / C2D
QSOP24	P3.0 / C2D

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
ADC0 ⁴	I _{ADC}	High Speed Mode 1 Msps, 12-bit conversions Normal bias settings V _{DD} = 3.0 V	—	1275	1700	μA
		Low Power Mode 350 ksps, 12-bit conversions Low power bias settings V _{DD} = 3.0 V	—	390	530	μA
Internal ADC0 Reference ⁵	I _{VREFFS}	High Speed Mode	—	700	790	μA
		Low Power Mode	—	170	210	μA
On-chip Precision Reference	I _{VREFP}		—	75	—	μA
Temperature Sensor	I _{TSENSE}		—	68	120	μA
Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3) ⁶	I _{DAC}		—	125	—	μA
Comparators (CMP0, CMP1)	I _{CMP}	CPMD = 11	—	0.5	—	μA
		CPMD = 10	—	3	—	μA
		CPMD = 01	—	10	—	μA
		CPMD = 00	—	25	—	μA
Comparator Reference	I _{CPREF}		—	24	—	μA
Voltage Supply Monitor (VMON0)	I _{VMON}		—	15	20	μA

Note:

1. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
2. Includes supply current from internal LDO regulator, supply monitor, and High Frequency Oscillator.
3. Includes supply current from internal LDO regulator, supply monitor, and Low Frequency Oscillator.
4. ADC0 power excludes internal reference supply current.
5. The internal reference is enabled as-needed when operating the ADC in low power mode. Total ADC + Reference current will depend on sampling rate.
6. DAC supply current for each enabled DA and not including external load on pin.

4.1.5 Power Management Timing

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCCLKs
Suspend Mode Wake-up Time	$t_{SUS-PENDWK}$	SYSCCLK = HFOSC0 CLKDIV = 0x00	—	170	—	ns
Snooze Mode Wake-up Time	$t_{SLEEPWK}$	SYSCCLK = HFOSC0 CLKDIV = 0x00	—	12	—	μ s

4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	PSS_{HFOSC0}	$T_A = 25\text{ }^{\circ}\text{C}$	—	0.5	—	%/V
Temperature Sensitivity	TS_{HFOSC0}	$V_{DD} = 3.0\text{ V}$	—	40	—	ppm/ $^{\circ}\text{C}$
High Frequency Oscillator 1 (72 MHz)						
Oscillator Frequency	f_{HFOSC1}	Full Temperature and Supply Range	70.5	72	73.5	MHz
Power Supply Sensitivity	PSS_{HFOSC1}	$T_A = 25\text{ }^{\circ}\text{C}$	—	300	—	ppm/V
Temperature Sensitivity	TS_{HFOSC1}	$V_{DD} = 3.0\text{ V}$	—	103	—	ppm/ $^{\circ}\text{C}$
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	PSS_{LFOSC}	$T_A = 25\text{ }^{\circ}\text{C}$	—	0.05	—	%/V
Temperature Sensitivity	TS_{LFOSC}	$V_{DD} = 3.0\text{ V}$	—	65	—	ppm/ $^{\circ}\text{C}$

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.8 Crystal Oscillator

Table 4.8. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	—	25	MHz
Crystal Drive Current	I_{XTAL}	XFCN = 0	—	0.5	—	μA
		XFCN = 1	—	1.5	—	μA
		XFCN = 2	—	4.8	—	μA
		XFCN = 3	—	14	—	μA
		XFCN = 4	—	40	—	μA
		XFCN = 5	—	120	—	μA
		XFCN = 6	—	550	—	μA
		XFCN = 7	—	2.6	—	mA

4.1.11 Temperature Sensor

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	V_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	751	—	mV
Uncalibrated Offset Error ¹	E_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	19	—	mV
Slope	M		—	2.82	—	mV/ $^{\circ}\text{C}$
Slope Error ¹	E_M		—	29	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity	LIN	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	—	-0.1 to 0.15	—	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	—	-0.2 to 0.35	—	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	—	-0.4 to 0.8	—	$^{\circ}\text{C}$
Turn-on Time	t_{ON}		—	3.5	—	μs
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset ^{2, 3}	E_{TOT}	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	-2.6	—	1.8	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-2.9	—	2.7	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	-3.2	—	4.2	$^{\circ}\text{C}$

Note:

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. The temp sensor error includes the offset calibration error, slope error, and linearity error. The values are based upon characterization and are not tested across temperature in production. The values represent three standard deviations above and below the mean. Additional information on achieving high measurement accuracy is available in AN929: Accurate Temperature Sensing with the EFM8 Laser Bee MCU Family.

4.1.13 Comparators

Table 4.13. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	100	—	ns
		-100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Low- est Power)	t_{RESP3}	+100 mV Differential	—	1.5	—	μs
		-100 mV Differential	—	3.5	—	μs
Positive Hysteresis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysteresis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	-6	—	mV
		CPHYN = 10	—	-12	—	mV
		CPHYN = 11	—	-24	—	mV
Positive Hysteresis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysteresis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	-4.5	—	mV
		CPHYN = 10	—	-9	—	mV
		CPHYN = 11	—	-18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS _{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V _{IN}		-0.25	—	V _{IO} +0.25	V
Input Pin Capacitance	C _{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N _{bits}		6			bits
Common-Mode Rejection Ratio	CMRR _{CP}		—	70	—	dB
Power Supply Rejection Ratio	PSRR _{CP}		—	72	—	dB
Input Offset Voltage	V _{OFF}	T _A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC _{OFF}		—	3.5	—	μV/°

4.1.14 Configurable Logic

Table 4.14. Configurable Logic

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t _{DLY}	Through single CLU Using an external pin	—	—	35.3	ns
		Through single CLU Using an internal connection	—	3	—	ns
Clocking Frequency	F _{CLK}	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.19 Absolute Maximum Ratings on page 30](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

Table 4.19. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO ²	V_{IO}		GND-0.3	$V_{DD}+0.3$	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}	$V_{IO} > 3.3\text{ V}$	GND-0.3	5.8	V
		$V_{IO} < 3.3\text{ V}$	GND-0.3	$V_{IO}+2.5$	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}		GND-0.3	$V_{DD}+0.3$	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	$T_A = -40\text{ °C to }105\text{ °C}$	-40	130	°C

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

Dimension	Min	Typ	Max
Note: <ol style="list-style-type: none"> All dimensions shown are in millimeters (mm) unless otherwise noted. Dimensioning and Tolerancing per ANSI Y14.5M-1994. This drawing conforms to JEDEC Solid State Outline MO-220. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components. 			

7.2 QFN32 PCB Land Pattern

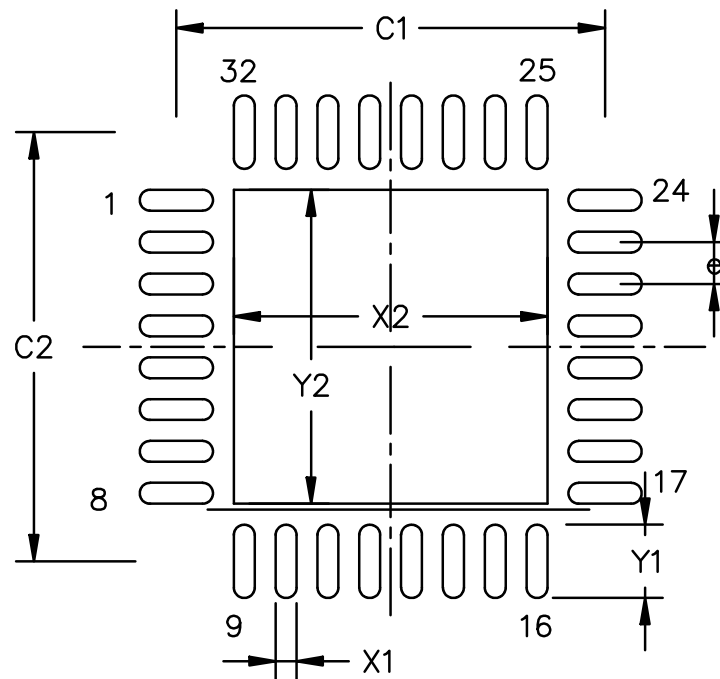


Figure 7.2. QFN32 PCB Land Pattern Drawing

Table 7.2. QFN32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	—	4.10
C2	—	4.10
X1	—	0.2
X2	—	3.0
Y1	—	0.7
Y2	—	3.0
e	—	0.4

Dimension	Min	Max
Note: <ol style="list-style-type: none"> 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification. 3. This Land Pattern Design is based on the IPC-7351 guidelines. 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm. 5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad. 6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release. 7. The stencil thickness should be 0.125 mm (5 mils). 8. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads. 9. A 2 x 2 array of 1.10 mm square openings on a 1.30 mm pitch should be used for the center pad. 10. A No-Clean, Type-3 solder paste is recommended. 11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components. 		

7.3 QFN32 Package Marking



Figure 7.3. QFN32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Typ	Max
aaa	0.20		
bbb	0.20		
ccc	0.10		
ddd	0.20		
theta	0°	3.5°	7°

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MS-026.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10. QSOP24 Package Specifications

10.1 QSOP24 Package Dimensions

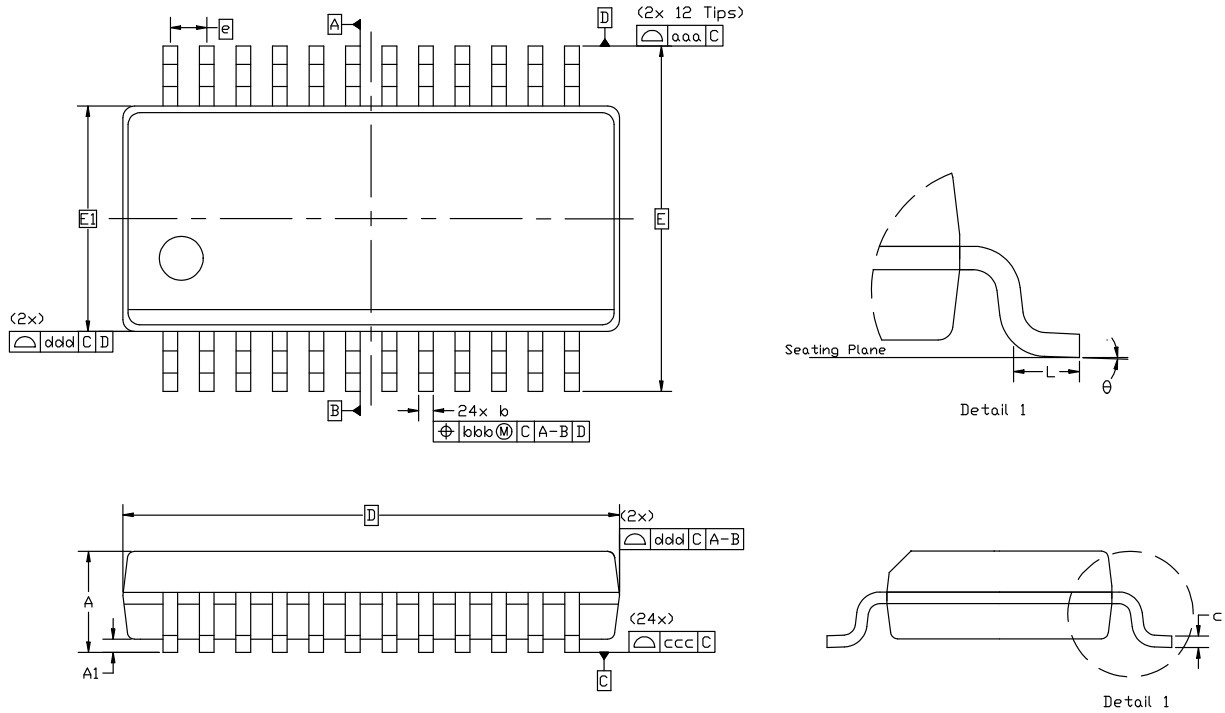


Figure 10.1. QSOP24 Package Drawing

Table 10.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10.3 QSOP24 Package Marking



Figure 10.3. QSOP24 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

11. Revision History

11.1 Revision 1.01

October 21st, 2016

Updated QFN24 center pad stencil description.

11.2 Revision 1.0

September 6th, 2016

Updated part numbers to revision B.

Updated many specifications with full characterization data.

Added a note regarding which DACs are available to [Table 2.1 Product Selection Guide on page 2](#).

Added specifications for [4.1.16 SMBus](#).

Added bootloader pinout information to [3.10 Bootloader](#).

Added CRC Calculation Time to [4.1.4 Flash Memory](#).

11.3 Revision 0.5

February 10th, 2016

Updated [Figure 5.2 Debug Connection Diagram on page 32](#) to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added S0 devices and information about the SMBus bootloader in [3.10 Bootloader](#).

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in [3.10 Bootloader](#).

Added mention of the pre-programmed bootloaders in [1. Feature List](#).

Updated all part numbers to revision B.

Added the C oscillator, which is now available on revision B.

Adjusted C1, C2, X2, Y2, and Y1 maximums for [7.2 QFN32 PCB Land Pattern](#).

Adjusted package markings for QFN32 and QSOP24 packages.

Filled in TBD minimum and maximum values for DAC Differential Nonlinearity in [Table 4.12 DACs on page 24](#).

11.4 Revision 0.4

Updated specification tables based on current device characterization status and production test limits.

Added bootloader section.

Added typical connection diagrams.

Corrected CLU connections in pin function tables.

11.5 Revision 0.3

Added information on the bootloader to [3.10 Bootloader](#).

Updated some characterization TBD values.

11.6 Revision 0.1

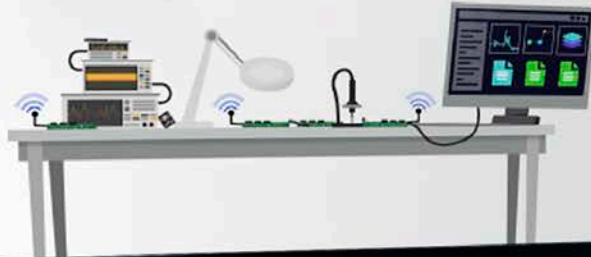
Initial release.

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